



LVDS 4x4 CROSSPOINT SWITCH

Check for Samples: SN65LVDT125A, SN65LVDS125A

FEATURES

- Signaling Rates >1.5 Gbps per Channel
- Supports Telecom/Datacom and HDTV Video Switching
- Non-Blocking Architecture Allows Each Output to be Connected to Any Input
- Compatible With ANSI TIA/EIA-644-A LVDS Standard
- 25 mV of Input Voltage Threshold Hysteresis
- · Propagation Delay Times, 900 ps Typical
- Inputs Electrically Compatible With LVPECL, CML and LVDS Signal Levels
- Operates From a Single 3.3-V Supply
- Integrated 110-Ω Line Termination Resistors Available With SN65LVDT125A

APPLICATIONS

- Clock Buffering/Clock Muxing
- · Wireless Base Stations
- High-Speed Network Routing
- HDTV Video Switching

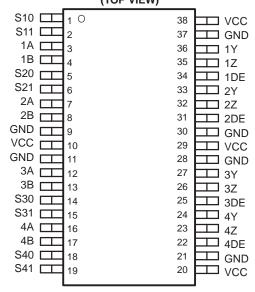
DESCRIPTION

The SN65LVDS125A and SN65LVDT125A are 4x4 nonblocking crosspoint switches. Low-voltage differential signaling (LVDS) is used to achieve signaling rates of 1.5 Gbps per channel. Each output driver includes a 4:1 multiplexer to allow any input to be routed to any output. Internal signal paths are fully differential to achieve the high signaling speeds while maintaining low signal skews. The SN65LVDT125A incorporates 110- Ω termination resistors for those applications where board space is a premium.

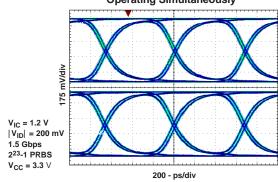
Designed to support signaling rates up to 1.5 Gbps for OC-12 clocks (622 MHz). The 1.5-Gbps signaling rate allows use in HDTV systems, including SMPTE 292 video applications requiring signaling rates of 1.485 Gbps.

The SN65LVDS125A and SN65LVDT125A are characterized for operation from -40°C to 85°C.

SN65LVDS125ADBT (Marked as LVDS125A) SN65LVDT125ADBT (Marked as LVDT125A) (TOP VIEW)



Eye Pattern of Two Outputs Operating Simultaneously





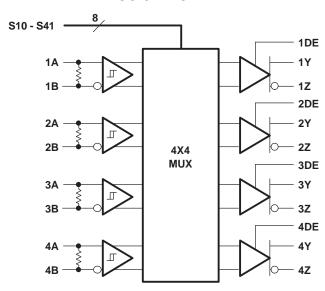
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

LOGIC DIAGRAM



Integrated 110- Ω Termination on LVDT Only

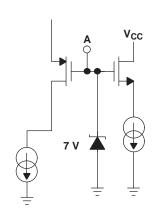
SN65LVDS125A Pin Description

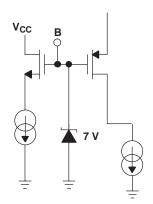
Pin Numbers	Pin Description
S10 - S41	Inputs; Input channel to out output channel selection control pins
1A, 2A, 3A, 4A	Inputs; Positive leg of LVDS data input
1B, 2B, 3B, 4B	Inputs; Negative leg of LVDS data input
1Y, 2Y, 3Y, 4Y	Outputs; Positive leg of LVDS data output
1Z, 2Z, 3Z, 4Z	Outputs; Negative leg of LVDS data output
1DE, 2DE, 3DE, 4DE	Inputs; Output port disable
V _{CC}	Input Voltage
GND	Ground

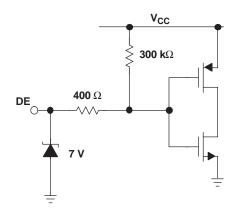


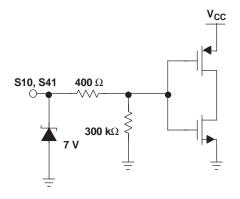
EQUIVALENT INPUT AND OUTPUT SCHEMATIC DIAGRAMS

INPUT LVDS125A









OUTPUT LVDS125A

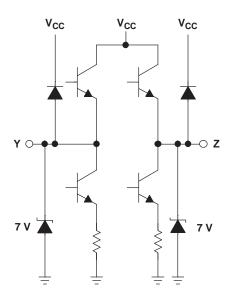




Table 1. CROSSPOINT LOGIC TABLES

OUTPUT CHANNEL 1			OUTPUT CHANNEL 2			OUTPUT CHANNEL 3			0	UTPUT CI	HANNEL 4
	TROL NS	INPUT SELECTED		ITROL INS	INPUT SELECTED		TROL NS	INPUT SELECTED		ITROL INS	INPUT SELECTED
S10	S11	1Y/1Z	S20	S21	2Y/2Z	S30	S31	3Y/3Z	S40	S41	4Y/4Z
0	0	1A/1B	0	0	1A/1B	0	0	1A/1B	0	0	1A/1B
0	1	2A/2B	0	1	2A/2B	0	1	2A/2B	0	1	2A/2B
1	0	3A/3B	1	0	3A/3B	1	0	3A/3B	1	0	3A/3B
1	1	4A/4B	1	1	4A/4B	1	1	4A/4B	1	1	4A/4B

PACKAGE DISSIPATION RATINGS

PACKAGE	CIRCUIT BOARD	T _A ≤ 25°C	DERATING FACTOR ⁽¹⁾	T _A = 85°C
	MODEL	POWER RATING	ABOVE T _A = 25°C	POWER RATING
TSSOP (DBT)	High-K ⁽²⁾	1772 mW	15.4 mW/°C	847 mW

- This is the inverse of the junction-to-ambient thermal resistance when board-mounded and with no air flow.
- In accordance with the High-K thermal metric definitions of EIA/JESD51-6.

THERMAL CHARACTERISTICS

PARAMETER			TEST CONDITIONS	VALUE	UNITS
θ_{JB}	Junction-to-board thermal resista	ance		40.3	°C/W
θ _{JC} Junction-to-case thermal resistance		nce		8.5	C/VV
_	Davies assumediation	Typical	V _{CC} = 3.3 V, T _A = 25°C, 750 MHz	356	mW
P_D	Device power dissipation	Maximum	V _{CC} = 3.6 V, T _A = 85°C, 750 MHz	522	mW

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range unless otherwise noted(1)

			UNITS	
Supply voltage range, V _{cc}			-0.5 V to 4 V	
Voltage range ⁽²⁾	S, DE		-0.5 V to 4 V	
	(A, B)	-0.5 V to 4 V		
	V _A - V _B (LVDT only)	1 V		
	(Y, Z)	-0.5 V to 4 V		
Clastrostatia dia sharas	Human body model (3)	All pins	±3 kV	
Electrostatic discharge	Charged-device model (4)	All pins	±500 V	
Continuous power dissipat	Continuous power dissipation			
Storage temperature range)		-65°C to 150°C	

- (1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.
- Tested in accordance with JEDEC Standard 22, Test Method A114-A. Tested in accordance with JEDEC Standard 22, Test Method C101.



RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}		3	3.3	3.6	V
High-level input voltage, V _{IH}	S10-S41, 1DE-4DE	2			V
Low-level input voltage, V _{IL}	S10-S41, 1DE-4DE			0.8	V
Magnitude of differential input values IV	LVDS	0.1			V
Magnitude of differential input voltage V _{ID}	LVDT	0.1		0.8	V
Input voltage (any combination of common-mode	e or input signals)	0		3.3	V
Junction temperature, T _J				140	°C
Operating free-air temperature, T _A ⁽¹⁾		-40		85	°C

⁽¹⁾ Maximum free-air temperature operation is allowed as long as the device maximum junction temperature is not exceeded.

TIMING SPECIFICATIONS

	PARAMETER			NOM	MAX	UNIT
t _{SET}	Input to select setup time			0.6		ns
t _{HOLD}	Input to select hold time	See Figure 7		0.2		ns
t _{SWITCH}	Select to switch output			1.2	1.6	ns

INPUT ELECTRICAL CHARACTERISTICS

over recommended operating conditions unless otherwise noted (1)

	PARAMETER		TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{IT+}	Positive-going differential input vo	ltage	See Figure 1			100	mV
V _{IT-}	Negative-going differential input v threshold	oltage	See Figure 1	-100			mV
V _{ID(HYS)}	Differential input voltage hysteres	is			25		mV
1	High level input current	1DE-4DE	V 2V			-10	
I _{IH}	High-level input current	S10-S41	$V_{IH} = 2 V$			20	μA
-	Law lawal imput avenue	1DE-4DE				-10	
I _{IL}	Low-level input current	S10-S41	$V_{IL} = 0.8 V$			20	μA
I _I	Input current		$V_I = 0 \text{ V or } 3.3 \text{ V, Second input at } 1.2 \text{ V (other input open for LVDT)}$	-20		20	μΑ
I _{I(OFF)}	Input current		$V_{CC} \le 1.5 \text{ V}, V_I = 0 \text{ V} \text{ or } 3.3 \text{ V}, \text{ Second input at } 1.2 \text{ V} \text{ (other input open for LVDT)}$	-20		20	μΑ
I _{IO}	Input offset current (I _{IA} - I _{IB}) ('LV	DS)	$V_{IA} = V_{IB}, 0 \le V_{IA} \le 3.3 \text{ V}$	-6		6	μΑ
	Termination resistance ('LVDT)		$V_{ID} = 300 \text{ mV}, V_{IC} = 0 \text{ V to } 3.3 \text{ V}$	90	110	132	
R _T Termination resistance('LVDT with power-off)		V_{ID} = 300 mV, V_{IC} = 0 V to 3.3 V, V_{CC} = 1.5 V	90	110	132	Ω	
C _T	Differential input capacitance				0.6		pF

⁽¹⁾ All typical values are at 25°C and with a 3.3 V supply.

NSTRUMENTS

OUTPUT ELECTRICAL CHARACTERISTICS

over recommended operating conditions unless otherwise noted(1)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$ V_{OD} $	Differential output voltage magnitude	Coo Figure 2	247	350	454	mV
$\Delta V_{OD} $	Change in differential output voltage magnitude between logic states	See Figure 2, V _{ID} = ±100 mV	-50		50	mV
V _{OC(SS)}	Steady-state common-mode output voltage		1.125		1.375	V
$\Delta V_{OC(SS)}$	Change in steady-state common-mode output voltage between logic states	See Figure 3	-50		50	mV
V _{OC(PP)}	Peak-to-peak common-mode output voltage			50	150	mV
I _{CC}	Supply current	$R_L = 100 \Omega, C_L = 1 pF$		107	145	mA
Ios	Short-circuit output current	V_{OY} or $V_{OZ} = 0 V$	-27		27	mA
I _{OSD}	Differential short circuit output current	V _{OD} = 0 V	-12		12	mA
I _{OZ}	High-impedance output current	$V_O = 0 \text{ V or } V_{CC}$	-1		±1	μΑ
Co	Differential output capacitance			1.2		рF

⁽¹⁾ All typical values are at 25°C and with a 3.3 V supply.

SWITCHING CHARACTERISTICS

over recommended operating conditions unless otherwise noted⁽¹⁾

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	Propagation delay time, low-to-high-level output		700	900	1200	
t _{PHL}	Propagation delay time, high-to-low-level output	San Figure 4	700	900	1200	
t _r	Differential output signal rise time (20%-80%)	See Figure 4		210	270	ps
t _f	Differential output signal fall time (20%-80%)			210	270	
t _{sk(p)}	Pulse skew (t _{PHL} - t _{PLH}) ⁽¹⁾			0	50	ps
t _{sk(o)}	Channel-to-channel output skew ⁽²⁾				150	ps
t _{sk(pp)}	Part-to-part skew ⁽³⁾				300	ps
t _{jit(per)}	Period jitter, rms (1 standard deviation) ⁽⁴⁾	750 MHz clock input ⁽⁵⁾ (see Figure 6)		0.4	3	ps
t _{jit(cc)}	Cycle-to-cycle jitter (peak) ⁽⁴⁾	750 MHz clock input ⁽⁶⁾ (see Figure 6)		4.7	13	ps
t _{jit(pp)}	Peak-to-peak jitter ⁽⁴⁾	1.5 Gbps 2 ²³ -1 PRBS input ⁽⁷⁾ (see Figure 6)		65	110	ps
t _{jit(det)}	Deterministic jitter, peak-to-peak (4)	1.5 Gbps 2 ⁷ -1 PRBS input ⁽⁸⁾ (see Figure 6)		56	90	ps
t _{PHZ}	Propagation delay, high-level-to-high-impedance output				6	
t _{PLZ}	Propagation delay, low-level-to-high-impedance output See Figure 5				6	20
t _{PZH}	Propagation delay, high-impedance -to-high-level output	e -to-high-level output			300	ns
t _{PZL}	Propagation delay, high-impedance-to-low-level output				300	

- $t_{\text{sk(p)}}$ is the magnitude of the time difference between the t_{PLH} and t_{PHL} of any output of a single device.
- $t_{sk(o)}$ is the maximum delay time difference between drivers over temperature, V_{CC} , and process.
- t_{sk(pp)} is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.
- Jitter specifications are based on design and characteriztion. Stimulus system jitter of 1.9 ps t_{jit(per)}, 16 ps t_{jit(per)}, 17 ps t_{jit(pp)}, and 7.2 ps Sitifullius system jitter of 1.9 ps $t_{jit(per)}$, 16 ps $t_{jit(per)}$, 17 ps $t_{jit(per)}$, 18 ps $t_{jit(per)}$, 19 ps t_{jit



PARAMETER MEASUREMENT INFORMATION

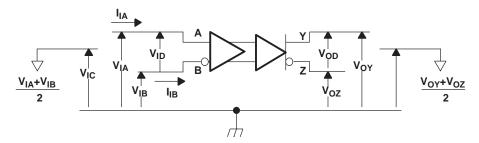


Figure 1. Voltage and Current Definitions

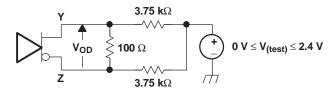
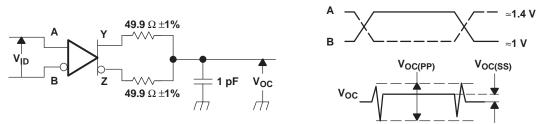
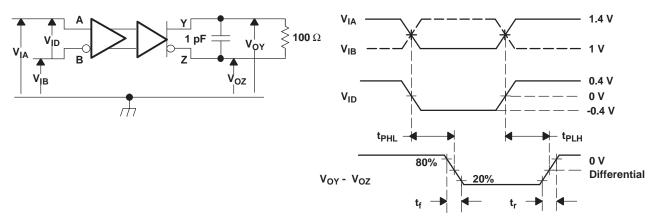


Figure 2. Differential Output Voltage (VoD) Test Circuit



NOTE: All input pulses are supplied by a generator having the following characteristics: t_r or $t_f \le 1$ ns, pulse-repetition rate (PRR) = 0.5 Mpps, pulse width = 500 ±10 ns; R_L = 100W; C_L includes instrumentation and fixture capacitance within 0,06 mm of the D.U.T.; the measurement of $V_{OC(PP)}$ is made on test equipment with a -3 dB bandwidth of at least 300 MHz.

Figure 3. Test Circuit and Definitions fot the Driver Common-Mode Output Voltage

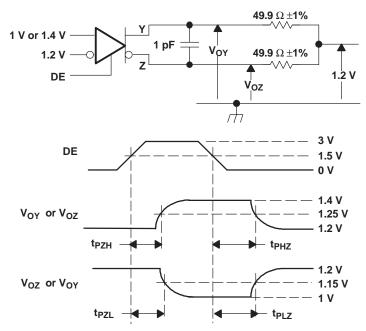


NOTE: All input pulses are supplied by a generator having the following characteristics: t_r or $t_r \le .25$ ns, pulse-repetition rate (PRR) = 0.5 Mpps, pulse width = 500 ± 10 ns . C_L includes instrumentation and fixture capacitance within 0,06 mm of the D.U.T.

Figure 4. Timing Test Circuit and Waveforms

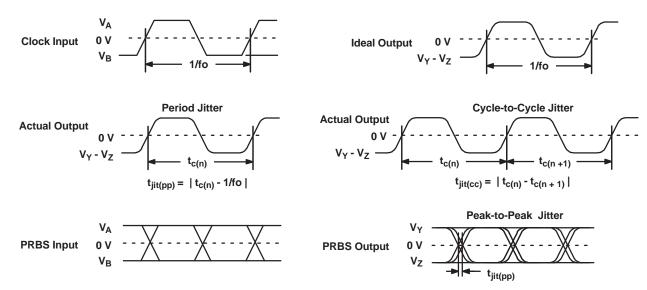


PARAMETER MEASUREMENT INFORMATION (continued)



NOTE: All input pulses are supplied by a generator having the following characteristics: t_r or $t_f \le 1$ ns, pulse-repetition rate (PRR) = 0.5 Mpps, pulse width = 500 ± 10 ns . C_L includes instrumentation and fixture capacitance within 0,06 mm of the D.U.T.

Figure 5. Enable and Disable Time Circuit and Definitions

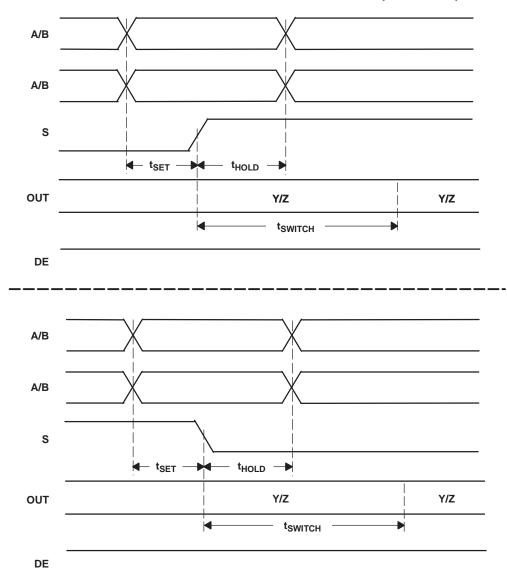


NOTE: All input pulses are supplied by an Agilent 81250 Stimulus System. The measurement is made on a TEK TDS6604 running TDSJIT3 application software.

Figure 6. Driver Jitter Measurement Waveforms



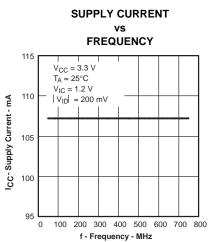
PARAMETER MEASUREMENT INFORMATION (continued)



NOTE: t_{SET} and t_{HOLD} times specify that data must be in a stable state before and after mux control switches.

Figure 7. Input to Select for Both Rising and Falling Edge Setup and Hold Times

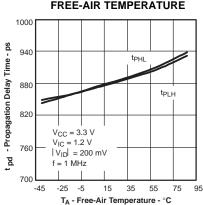






TYPICAL CHARACTERISTICS PROPAGATION DELAY TIME

FREE-AIR TEMPERATURE



PROPAGATION DELAY TIME

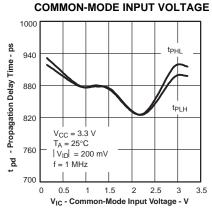


Figure 10.

Figure 8.

PEAK-TO-PEAK JITTER vs

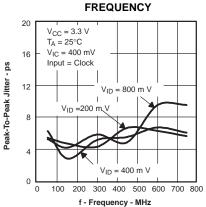


Figure 11.

PEAK-TOOPEAK JITTER VS **DATA RATE**

Figure 9.

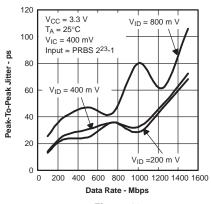


Figure 12.

PEAK-TO-PEAK JITTER FREQUENCY

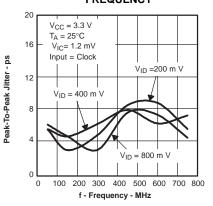


Figure 13.

PEAK-TO-PEAK JITTER vs **DATA RATE**

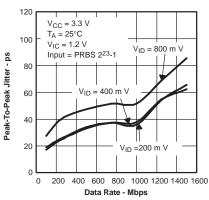
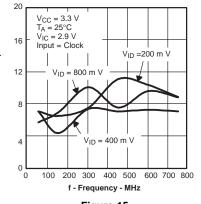


Figure 14.

PEAK-TOOPEAK JITTER vs **FREQUENCY**



Peak-To-Peak Jitter

Figure 15.

PEAK-TO-PEAK JITTER VS

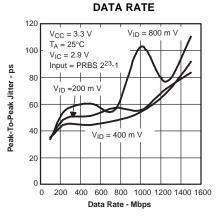


Figure 16.



TYPICAL CHARACTERISTICS (continued)

PEAK-TO-PEAK JITTER

FREE-AIR TEMPERATURE

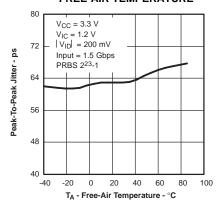


Figure 17.

PEAK-TO-PEAK JITTER



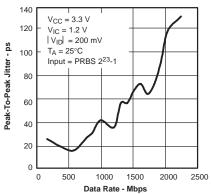


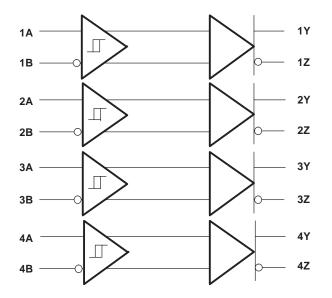
Figure 18.



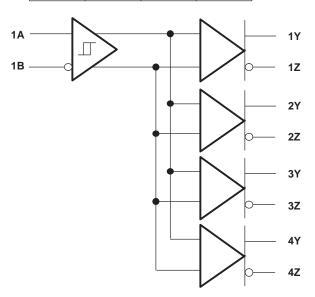
APPLICATION INFORMATION

CONFIGURATION EXAMPLES

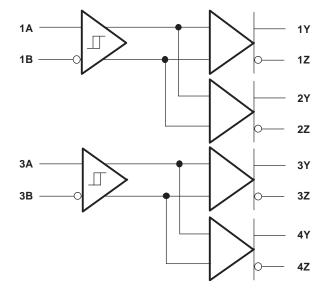
S10	S11	S20	S21
0	0	0	1
S30	S31	S40	S41
1	0	1	1



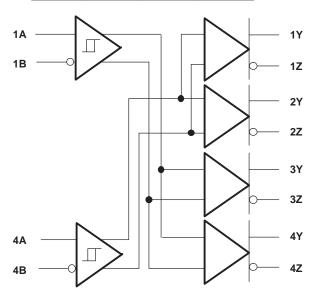
S10	S11	S20	S21
0	0	0	0
S30	S31	S40	S41
0	0	0	0



S10	S11	S20	S21		
0	0	0	0		
S30	S31	S40	S41		
- 1	Δ.	4	0		



S10	S11	S20	S21
1	1	1	1
S30	S31	S40	S41
0	0	0	0





TYPICAL APPLICATION CIRCUITS (ECL, PECL, LVDS, etc.)

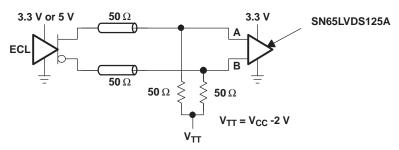


Figure 20. Low-Voltage Positive Emitter-Coupled Logic (LVPECL)

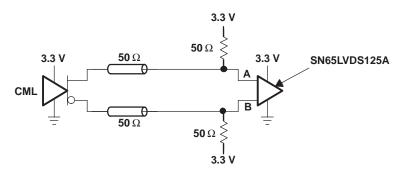


Figure 21. Current-Mode Logic (CML)

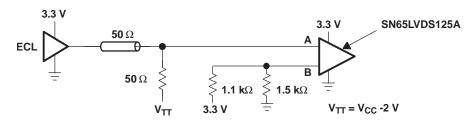


Figure 22. Single-Ended (LVPECL)

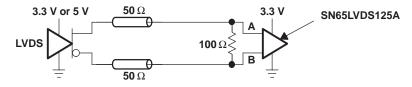


Figure 23. Low-Voltage Differential Signaling (LVDS)

See the EVM Users Guide (SLLU064) for example board layout and schematics examples.





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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing		Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Top-Side Markings	Samples
SN65LVDS125ADBT	ACTIVE	TSSOP	DBT	38	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	LVDS125A	Samples
SN65LVDS125ADBTG4	ACTIVE	TSSOP	DBT	38	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	LVDS125A	Samples
SN65LVDS125ADBTR	ACTIVE	TSSOP	DBT	38	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	LVDS125A	Samples
SN65LVDS125ADBTRG4	ACTIVE	TSSOP	DBT	38	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	LVDS125A	Samples
SN65LVDT125ADBT	ACTIVE	TSSOP	DBT	38	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	LVDT125A	Samples
SN65LVDT125ADBTG4	ACTIVE	TSSOP	DBT	38	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	LVDT125A	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between

the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight

in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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⁽⁴⁾ Only one of markings shown within the brackets will appear on the physical device.



PACKAGE OPTION ADDENDUM

24-Jan-2013

continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

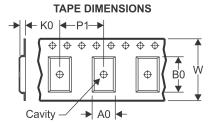
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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65LVDS125ADBTR	TSSOP	DBT	38	2000	330.0	16.4	6.9	10.2	1.8	12.0	16.0	Q1

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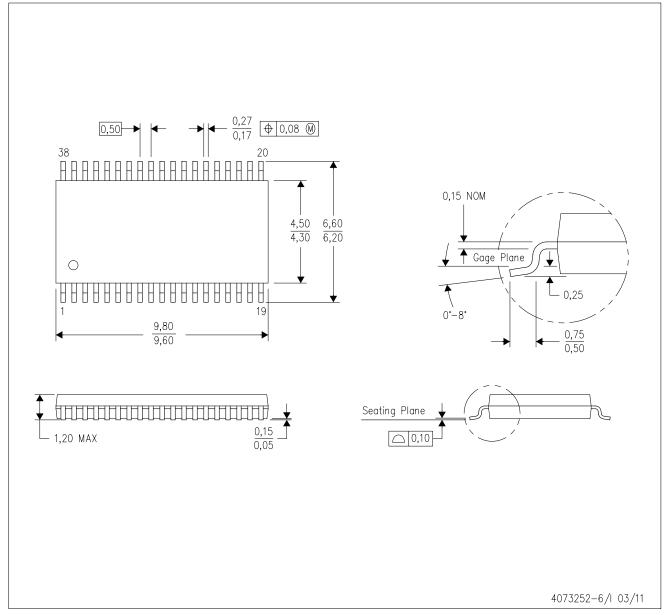


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
SN65LVDS125ADBTR	TSSOP	DBT	38	2000	367.0	367.0	38.0	

DBT (R-PDSO-G38)

PLASTIC SMALL OUTLINE



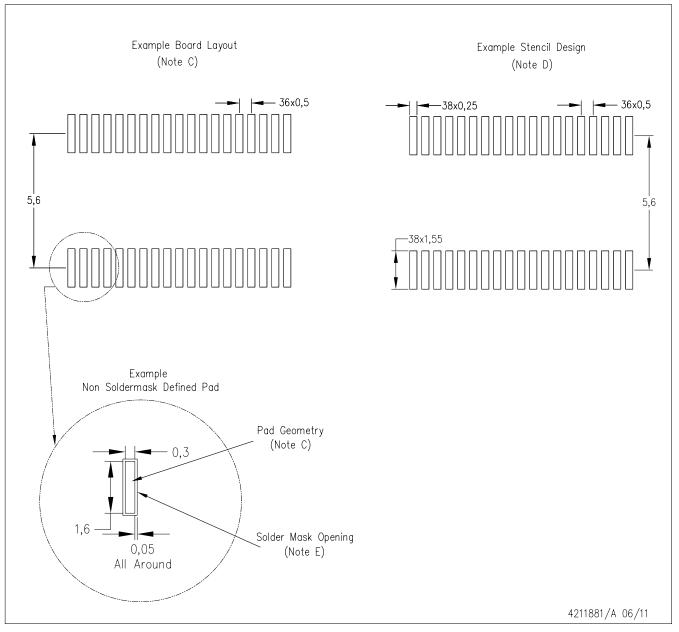
NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion.
- D. Falls within JEDEC MO-153.



DBT (R-PDSO-G38)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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